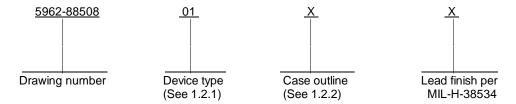
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SHEET REV SHEET REV STATU OF SHEETS PMIC N/A	S		SHE	ET	ED BY					5	6	7 ELECT		9 S SU	10	11 CENT	12		
SHEET REV SHEET REV STATU OF SHEETS PMIC N/A STAN		ED ED	SHE PRE Gary	EET PARE Zahn	1	1			4	5 DEFE	6 ENSE I	7 ELECT DA	8 RONIC YTON,	9 CS SU OHIC	10 JPPLY) 4544	11 CENT 44	12 ER	13	
SHEET REV SHEET REV STATU OF SHEETS PMIC N/A STAN MI DR THIS E AV FOR U	DARDIZE LITARY RAWING DRAWING (AILABLE USE BY AL	IS L	SHE PRE Gary CHE Mich	ET PARE Zahn CKED nael C	BY	1			4 MI(5 DEFE	6 ENSE I	7 ELECT DA	8 RONIC	9 CS SU OHIO	10 JPPLY 0 4544	11 CENT	12 ER	13 T	
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1. SCOPE

- 1.1 <u>Scope</u>. This drawing describes device requirements for class H hybrid microcircuits to be processed in accordance with MIL-H-38534.
 - 1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:



1.2.1 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

Device type	Generic number	Circuit function	Conversion time		
01	ADC-HX	12-bit A/D Converter	20 µs		
02	ADC-HZ,MNADC87H	12-bit A/D Converter	8 µs		

1.2.2 <u>Case outline(s)</u>. The case outline(s) shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

X See figure 1 (32-lead, 1.72" x 1.10" x .235"), dual-in-line package

1.3 Absolute maximum ratings.

Positive supply voltage (V_{CC}) Negative supply voltage (V_{EE}) Logic supply voltage (V_{DD}) Analog input voltage Buffer input voltage Digital inputs Junction temperature (T_J) Storage temperature Power dissipation (P_D), $T_C = +25^{\circ}C$ Lead temperature (soldering, 10 seconds)	-0.3 to +18 V dc +0.3 to -18 V dc -0.3 to +7 V dc -25 V ±V _S +5.5 V +175° C -65° C to +150° C 2 W +300° C
Thermal resistance:	
Junction-to-case ($\Theta_{ extsf{JC}}$)	13° C/W
Junction-to-ambient (Θ_{JA})	41° C/W

1.4 Recommended operating conditions.

Positive supply voltage range (V _{CC})	+14.5 to +15.5 V dc
Negative supply voltage range (V _{FF})	-14.5 to -15.5 V dc
Logic supply voltage range (V _{DD})	+4.5 to +5.5 V dc
Ambient operating temperature range (T _A)	-55° C to +125° C

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2. APPLICABLE DOCUMENTS

2.1 Government specifications and standard. Unless otherwise specified, the following specifications and standard of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATIONS

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

MIL-H-38534

- Hybrid Microcircuits, General Specification for.

STANDARD

MILITARY

MII -STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specifications, and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.
 - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein and figure 1.
 - 3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.
- 3.2.3 <u>Functional diagram and input connection table</u>. The functional diagramand input connection table shall be as specified on figure 3.
 - 3.2.4 Truth table(s). The truth table(s) shall be as specified on figure 4.
 - 3.2.5 <u>Timing diagram</u>. The timing diagram shall be as specified on figure 5.
- 3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

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Test	l Symbol	Conditions <u>1/</u> -55° C ≤ T _A ≤ +125° C unless otherwise specified	l Group A	 <u>Limits</u>		l _ Unit
			subgroups 	 Min 	 Max 	
Resolution	RES	 Digital and serial	1,2,3	12		 BIT
Unipolar coding	UC L	 Complementary binary (see 4.3.1b)	7,8		 	
Bipolar coding	 BC 	 Complementary offset binary (see 4.3.1b)	 7,8 	 	 	
Unipolar input (coding)		 0 to +10 V range, T _A = +25° C See figure 3 for input connections (see 4.3.1b)	 7 	 	 	
Unipolar input (coding)		 0 to +5 V range, T _A = +25°C See figure 3 for input connections (see 4.3.1b)	 7 	 	 	
Bipolar input (coding)	 	 -2.5 to +2.5 V range, T _A = +25° C See figure 3 for input connections (see 4.3.1b)	 7 	 	 	
Bipolar input (coding)		 -5 to +5.5 V range, T _A = +25° C See figure 3 for input connections (see 4.3.1b)	 7 	 	 	
Buffer bias I	 BIAS 	 T _A = +25°C <u>2</u> /	 1 		 250 	 nA
Buffer offset error	 BUFOE		1,2,3		10	 mV
Nonlinearity	 NL	 End-point method	 4	<u> </u>	0.5	 LSB
			5,6	<u> </u>	1 1	
Differential nonlinearity	 DNL 		4	 -0.75	+0.75	 _ LSB
			5,6	 -1	 +1	<u> </u>
Differential nonlinearity drift	 ΔDNL I/ΛΤ	 T _A = -55°C, +125°C	 8 		 1.22	 ppm/°(

See footnotes at end of table.

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Test	Symbol	Conditions 1/	Group A	Limits		 _ Unit
		-55° C ≤ T _A ≤ +125° C unless otherwise specified 	subgroups 	 Min 	 Max 	
Unipolar gain error	UGE	0 V to 10 V range	4	 	0.2	 %FSR
			5,6	<u> </u>	0.4	<u> </u>
Unipolar gain error drift	 ΔUGE /ΔT 	 0 V to 10 range T _A = -55° C, +125° C 	 8 	 	 20 	 ppmFSR /°C
Bipolar gain error	BGE	 -10 V to +10 V range	4		0.2	 %FSR
			 5,6	<u> </u>	0.4	<u> </u>
Bipolar gain error drift	 ΔBGE /ΔT 	 T _A = -55° C, +125° C -10 V to +10 V range See figure 3 for input connections	 8 		 20 	 ppmFSR /°C
Unipolar offset error	 UOE	 0 to +10 V range See figure 3 for input	4	 	0.1	 %FSR
		connections	5,6	<u> </u>	0.2	<u> </u>
Unipolar offset error drift	 ΔUOE /ΔT 	T _A = -55°C, +125°C 0 to +10 V range See figure 3 for input connections	8		 5 	 ppm/° C
Bipolar offset error	 BZE	 -10 to +10 V range	1	<u> </u>	0.2	 %FSR
	<u> </u>	See figure 3 for input connections	 2,3	 	0.4	<u> </u>
Bipolar offset gain error	 ΔBZE /ΔT 	 T _A = -55° C, +125° C -10 V to +10 V range See figure 3 for input connections	 8 		 10 	 ppm/°C
No missing codes	 NMC	 Abbreviated test	 4,5,6	 pass		 BIT

See footnotes at end of table.

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	TABLE	l. Electrical performance characteristic	<u>s</u> - Continued.			
Test	 Symbol	Conditions 1/	 Group A	Limits		 _ Unit
	 	-55° C ≤ T _A ≤ +125° C unless otherwise specified 	subgroups 	 Min 	 Max 	
Conversion time	 t _C 	Device 01 See figure 5 Device 02	 9,10,11 		 20 8	 _ µs _
Internal reference error	 V _{REF} 	 From 6.300 V T _A = +25° C	 1 	 -126 	 +126 	 mV
Internal reference error drift	 V _{REF} /ΔT	 T _A = -55°C, +125°C	8		 20 	ppm/° C
Serial/parallel match	i IMTCH I	 Random codes T _A = +25° C	 7 	 pass 		
Digital output voltage _(high)	Î I ^V OH I	 2 TTL loads	1,2,3	 2.4 	 	 V
Digital output voltage (low)	 V _{OL} 	 2 TTL loads 	 1,2,3 		 0.4 	 V
Power supply rejection ratio (low)	 PSRR 	 V _S = ±5%	 1,2,3 	 	0.004	 %/%V _S
Quiescent supply current: Positive supply	 ICC	 V _{CC} = +15.5 V	 1,2,3		 35	 mA
Negative supply	ļΙ _{ΕΕ}	V _{EE} = -15.5 V			-40	
Logic supply	 I _{DD} 	 V _{DD} = 5.5 V 	 	 <u> </u>	 124 	 <u> </u>
Power dissipation	IP _D	 Nominal supply voltages	1,2,3		1.69	į W

1/ Unless otherwise specified the following conditions only:

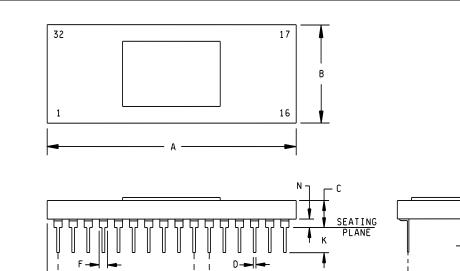
 $V_{CC} = +15 \text{ V dc}$ $V_{EE} = -15 \text{ V dc}$ $V_{DD} = +5 \text{ V dc}$ $V_{DG} = +0.8 \text{ V dc}$

Logic "1" = +2.0 V dc VFSR = 20 V

Bipolar operation

2/ Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to limits specified in table I for all lots not specifically tested.

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 Dim	 Inches		 Millimeters	
<u> </u> 	l Min	 Max	 Min	
 A	 	 1.720	 	 43.69
 B	 .880	1.100	22.35	 27.94
i I C		.235	 	 5.97
 D	.016	.021	0.41	 0.53
l F	.040 TYP		1.02	ΓΥΡ Ι
 G	.040 111 .100 BASIC			BASIC

 Inche	 Inches		neters
 Min	 <u> Max</u>	 Min	 Max
 .090	 .110	 2.29	 2.79
 .009	.015	0.23	0.38
1150	 211	 3.81	5.36
İ	İ	İ	23.37
İ	İ		 1.52
	 Min	Min Max	Min Max Min

NOTES:

- Leads in true position within 0.010 inch (0.25 mm) R at NMC at seating plane.
 PIN numbers shown for reference only. Pin 1 index is required.

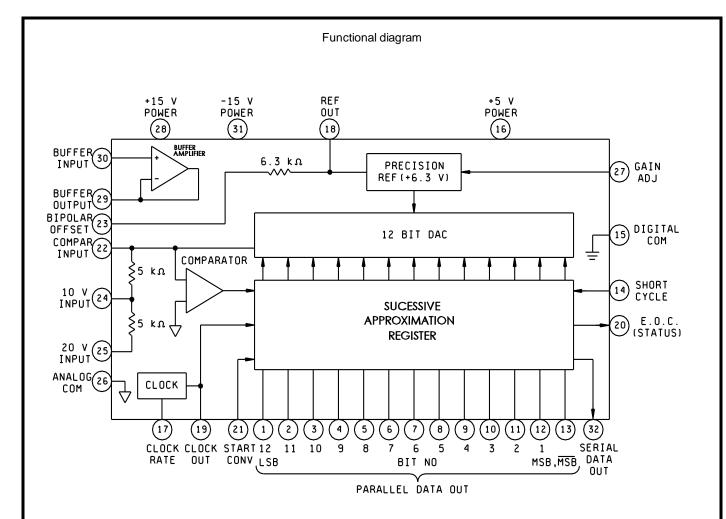
FIGURE 1. Case outline.

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Device types	 01 and 02	 Device types	
Case outlines	İ	Case outlines	 X
	Terminal symbol		
Terminal number		Terminal number	Terminal symbol
<u> </u>	Bit 12 out (LSB)	17	Clock rate
2			
	Bit 11 out	<u> 18 </u>	Ref out
3	 Bit 10 out	 <u> 19 </u>	Clock out
4	 Bit 9 out	 <u> </u> 20	E.O.C. (status)
<u>5</u>			
	Bit 8 out	21	Start convert
6			
	Bit 7 out	22	Compar iput
7			
	Bit 6 out	23	Bipolar offset
8	 Bit 5 out	 24	10 v range
9			
	Bit 4 out	25	20 v range
10	Bit 3 out	 26	Analog com
11			
	Bit 2 out	27	Gain ADJ
			IV _{CC} I
12	Bit 1 out (MSB)	28	
13	 Bit 1 out (MSB)	 29	Buffer output
14			
	Short cycle	<u> </u> 30	Buffer input
15	Digital com	31	V _{EE}
 16 	I IV _{DD}	 32 	 Serial output

FIGURE 2. <u>Terminal connections</u>.

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Input connection table

 Input volt	!	/ithout buffer	hasa nina	 Input PIN	 <u>Wit</u>	hout buffer	
range	Input PIN	Connect t	nese pins	PIN 	Connect	these pins to	gether
 0 to +5 V	24	22 to 25	23 to 26	30	22 to 25	23 to 26	29 to 24
0 to +10 V ±2.5 V	24	22 to 25	23 to 26	30 30	22 to 25	23 to 26 23 to 22	29 to 24 29 to 24
±5 V ±10 V	24 25		23 to 22 23 to 22	30 30		23 to 22 23 to 22	29 to 24 29 to 25
	1		1	ll .	1		1

FIGURE 3. Functional diagram and input connection table.

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Unipolar coding table

 Input rang	ge ge	Complen binary co	•
0 to + 10 V	 0 to +5 V	İ I MSB	LSB
 +9.9976 V +8.7500 V +7.5000 V +5.0000 V +2.5000 V +1.2500 V +0.0024 V +0.0000 V	 +4.9988 V +4.3750 V +3.7500 V +2.5000 V +1.2500 V +0.6250 V +0.0012 V +0.0000 V	 0000 0000 0001 1111 0011 1111 0111 1111 1101 1111 1111 1111	1111 1111 1111 1111 1111 1110

Bipolar coding table

			Complementary offset binary		Compleme	entary two's ment
±10 V	 ±5 V	 ±2.5 V	 MSB	LSB	 MSB	LSB
+9.9951 V +7.5000 V +5.0000 V 0.0000 V	+4.9976 V +3.7500 V +2.5000 V +0.0000 V	+2.4988 V +1.8750 V +1.2500 V +0.0000 V -1.2500 V	 0000 0001 0011 0111	1111 1111 1111 1111 1111 1111	1000 000 1001 11 ² 1011 11 ² 1111 11 ² 0011 11 ²	11 1111 11 1111 11 1111
-7.5000 V -9.9951 V -10.0000 V	-3.7500 V -4.9976 V -5.0000 V	-1.8750 V -2.4988 V -2.5000 V	1101 1111 1111	1111 1111 1111 1110 1111 1111	0011 11 ² 0111 11 ² 0111 11 ²	

FIGURE 4. Truth tables.

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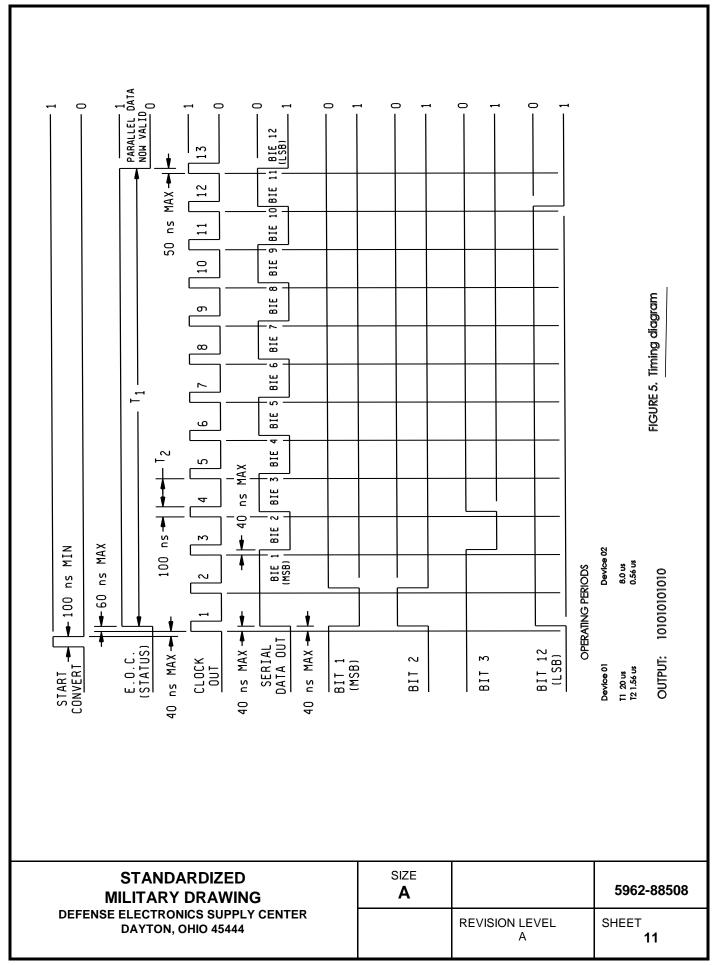


TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5008, group A test table)
Interim electrical parameters	1
Final electrical test parameters	1*,2,3,4,5,6,7, 8,9,10,11
Group A test requirements	1,2,3,4,5,6,7,8, 9,10,11
Group C end-point electrical parameters	1

^{*} PDA applies to subgroup 1.

- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534 (see 6.6 herein).
- 3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall submit for DESC-ECC review and approval electrical test data (variables format) on 22 devices from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in QML-38534 (see 6.6 herein). The certificate of compliance submitted to DESC-ECC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.
 - 4. QUALITY ASSURANCE PROVISIONS
 - 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-H-38534.
- 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_{Δ} as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.
 - 4.3.1 Group A inspection. Group A inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 7 and 8 shall include verification of input-to-output coding (see figure 4 herein).
 - 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.
 - 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_{Δ} as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
 - 4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.
 - 5. PACKAGING
 - 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.
 - 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for original equipment design applications and logistic support of existing equipment.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings.

Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECC, telephone (513) 296-8527.

- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECC, Dayton, Ohio 45444, or telephone (513) 296-8525.
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in QML-38534. Additional sources will be added to QML-38534 as they become available. The vendors listed in QML-38534 have agreed to this drawing and a certificate of compliance (see 3.7 herein) has been submitted to and accepted by DESC-ECC.

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STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 91-10-22

Approved sources of supply for SMD 5962-88508 are listed below for immediate acquisition only and shall be added to QML-38534 during the next revision. QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECC. This bulletin is superseded by the next dated revision of QML-38534.

 Standardized military drawing PIN	 Vendor CAGE number 	 Vendor similar PIN <u>1</u> /
 5962-8850801XX	 50721 	 ADC-HX/883B
 5962-8850802XX 	 50721 50507	 ADC-HX/883B MNADC87H/B

1/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE <u>number</u>	Vendor name and address
50507	Unitrode Corporation Micro Networks Division 324 Clark Street Worcester, MA 01606
50721	Datel, Incorporated 11 Cabot Boulevard Mansfield, MA 02048

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.